### Electron Microscopy
- FEI Helios Nanolab 600i FIB/SEM
- FEI Quanta 600i Environmental SEM
- FEI Talos F200x TEM/STEM
- FEI Tecnai T12
- JEOL JSM-7000f Field Emission SEM
- PHENOM SEM
- TESCAN S8252G Raman SEM/FIB*

### Mechanical Testing
- MARK-1 ESM 1500
- MTS Alliance RT/100
- INSTU-MET Renew 1125
- SATEC SONNTAG Fatigue Testing System SF-1-U
- DIC Fatigue Dynamics RBF-200 Rotating Bending Fatigue
- DSI Gleeble 3500-GTC
- MTS Exceed E22 Impact Tester
- MTS Landmark 370.10
- MTS Landmark 370.25
- MTS 312.21 Top Actuator
- MTS 312.21 Hydraulic Grips
- MTS 312.21 Bending Under Tension
- MTS 312.41
- MTS 810 Material Test System 318.50
- Extensometers
- Digital Image Correction
- Heater and Cooling Furnaces

### Scanning Probe & Optical Microscopy
- ASYLUM MFP-3D Scanning Probe Microscope
- DIGITAL INSTRUMENTS Atomic Force Microscope
- KEYENCE VHX-5000
- D-600 Profilometer
- WITEC Laser Confocal Raman Microscope

### Optical & Electrical Characterization
- CARY 5G UV-VIS Spectrometer
- Four Point Probe/ Electrical Probe Station
- FTIR Spectrometer/Ellipsometer
- Janis SHI-4-2 Cryostat
- HL5500 Hall Effect Measurement System
- Solar Simulator w/EQE
- WOOLLAM M-2000 Ellipsometer

### Nanofabrication
- Class 1,000 Clean rooms
- ABM UV Mask Aligner
- AUTO GLOW 200 Reactive Ion Etcher
- KARL SUSS MJB3 UV400 Mask Aligners
- ULVAC-RIKO MILO-5000 Rapid Thermal Annealer
- Diffusion Furnace
- High Temperature Furnace
- Rapid Thermal Annealer
- Vacuum Furnace
- Wet & Dry Oxidation Furnaces
- TPT hb05 Wire Bonder

### Thin Film Deposition
- AJA Sputtering System
- ANGSTROM Thermal Evaporator
- Tabletop Gold Sputter Coater
- High Temperature Thermal Evaporator
- AJA UHV Multi-Technique Deposition System
- Semicore Sputtering System

### Mass Spectrometry
- CAMECA APT LEAP 4000X SI
- IONTOF TOF-SIMS V*
- SCIEX 5500 Triple Quad
- SCIEX X500R QToF

### X-Ray Diffraction & Computed Tomography
- PANALYTICAL Empyrean Modular X-Ray Diffractometer*
- PANALYTICAL X’Pert Pro X-Ray Diffractometer
- ZEISS Versa 520 XCT*

### X-Ray Photoelectron Spectroscopy*

For more detailed information on instrumentation capabilities, to request access or assistance, and view user rates, please visit: Mines.edu/Shared-Facilities

* Instrument has in situ capabilities
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